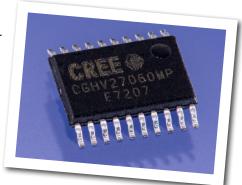


# **CGHV27060MP**

# 60 W, DC - 2700 MHz, 50 V, GaN HEMT for LTE and Pulse Radar Applications

Cree's CGHV27060MP is a 60W gallium nitride (GaN) high electron mobility transistor (HEMT) housed in a small plastic SMT package 4.4mm x 6.5mm. The transistor is a broadband device with no internal input or output match which allows for the agility to apply to a wide range of frequencies from UHF thru 2.7GHz. The CGHV27060MP makes for an excellent transistor for pulsed applications at UHF, L Band or low S Band (<2.7GHz). Additionally, the transistor is well suited for LTE micro basestation amplifiers in the power class of 10 to 15W average power in high efficiency topologies such as Class A/B, F or Doherty amplifiers.



PN: CGHV27060MP

# Typical Performance Over 2.5 - 2.7 GHz (T<sub>c</sub> = 25°C) of Demonstration Amplifier

Parameter	2.5 GHz	2.6 GHz	2.7 GHz	Units
Gain @ 41.5 dBm Avg P <sub>оит</sub>	18.25	18.5	18.25	dB
ACLR @ 41.5 dBm Avg P <sub>оит</sub>	-34	-37	-38	dBc
Drain Efficiency @ 41.5 dBm Avg P <sub>out</sub>	33	35	33	%

#### Note:

Measured in the CGHV27060MP-TB amplifier circuit, under WCDMA 3GPP test model 1, 64 DPCH, 45% clipping, PAR = 7.5 dB @ 0.01% Probability on CCDF,  $V_{DD}$  = 50 V,  $I_{DS}$  = 125 mA.

## Typical Performance Over 2.5 - 2.7 GHz (T<sub>c</sub> = 25°C) of Demonstration Amplifier

Parameter	2.5 GHz	2.6 GHz	2.7 GHz	Units
Gain	16.5	16.3	16.2	dB
Output Power	84	82	79	W
Drain Efficiency	71	69	65	%

#### Note:

Measured in the CGHV27060MP-TB amplifier circuit, under pulse width 100  $\mu$ s, 10% duty cycle,  $P_{IN}$  = 33 dBm.

### Features - WCDMA

- 2.5 2.7 GHz Reference Design Amplifier
- 18.5 dB Gain at 14 W P<sub>AVF</sub>
- -35 dBc ACLR at 14 W P<sub>AVE</sub>
- 35% Efficiency at 14 W P<sub>AVE</sub>
- · High Degree of DPD Correction Can be Applied

### Features - Pulsed

- 16.5 dB Gain at Pulsed P<sub>SAT</sub>
- 70% Efficiency at Pulsed P<sub>SAT</sub>
- 80W at Pulsed P<sub>SAT</sub>



### Absolute Maximum Ratings (not simultaneous) at 25°C Case Temperature

Parameter	Symbol	Rating	Units	Conditions
Drain-Source Voltage	V <sub>DSS</sub>	150	Volts	25°C
Gate-to-Source Voltage	$V_{GS}$	-10, +2	Volts	25°C
Storage Temperature	T <sub>STG</sub>	-65, +150	°C	
Operating Junction Temperature	T <sub>J</sub>	225	°C	
Maximum Forward Gate Current	I <sub>GMAX</sub>	10.4	mA	25°C
Maximum Drain Current <sup>1</sup>	I <sub>DMAX</sub>	6.3	А	25°C
Soldering Temperature <sup>2</sup>	T <sub>s</sub>	245	°C	
Thermal Resistance, Junction to Case <sup>3</sup>	$R_{_{ heta JC}}$	2.6	°C/W	85°C, P <sub>DISS</sub> = 52 W
Thermal Resistance Pulsed 10%, 100 µs, Junction to Case	$R_{_{\theta JC}}$	1.95	°C/W	85°C, P <sub>DISS</sub> = 62W, 100 μs/10%
Case Operating Temperature <sup>4</sup>	T <sub>c</sub>	-40, +90	°C	CW

#### Note:

# Electrical Characteristics (T<sub>c</sub> = 25°C)

Characteristics	Symbol	Min.	Тур.	Max.	Units	Conditions
DC Characteristics¹						
Gate Threshold Voltage	$V_{\rm GS(th)}$	-3.8	-3.0	-2.3	V <sub>DC</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10.4 mA
Gate Quiescent Voltage	$V_{GS(Q)}$	-	-2.7	-	V <sub>DC</sub>	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 125 mA
Saturated Drain Current <sup>2</sup>	I <sub>DS</sub>	8.4	10.4	-	Α	$V_{DS} = 6.0 \text{ V, } V_{GS} = 2.0 \text{ V}$
Drain-Source Breakdown Voltage	$V_{_{\mathrm{BR}}}$	150	-	-	V <sub>DC</sub>	$V_{GS}$ = -8 V, $I_{D}$ = 10.4 mA
RF Characteristics <sup>5</sup> (T <sub>c</sub> = 25°C, F <sub>0</sub> = 2.7 GH	z unless otherw	vise noted)				
Saturated Output Power <sup>3,4</sup>	P <sub>SAT</sub>	-	80	-	W	V <sub>DD</sub> = 50 V, I <sub>DQ</sub> = 125 mA
Pulsed Drain Efficiency <sup>3,4</sup>	η	-	70	-	%	$V_{DD}$ = 50 V, $I_{DQ}$ = 125 mA, $P_{OUT}$ = $P_{SAT}$
Gain <sup>3,4</sup>	G	-	16.5	-	dB	$V_{DD}$ = 50 V, $I_{DQ}$ = 125 mA, $P_{OUT}$ = $P_{SAT}$
Gain <sup>6</sup>	G	-	18.5	-	dB	$V_{DD} = 50 \text{ V, } I_{DQ} = 125 \text{ mA, } P_{OUT} = 41.5 \text{ dBm}$
WCDMA Linearity <sup>6</sup>	ACLR	-	-35	-	dBc	$V_{DD} = 50 \text{ V, } I_{DQ} = 125 \text{ mA, } P_{OUT} = 41.5 \text{ dBm}$
Drain Efficiency <sup>6</sup>	η	-	34	-	%	$V_{DD} = 50 \text{ V, } I_{DQ} = 125 \text{ mA, } P_{OUT} = 41.5 \text{ dBm}$
Output Mismatch Stress <sup>3</sup>	VSWR	-	-	TBD	Ψ	No damage at all phase angles, $V_{\rm DD}$ = 50 V, $I_{\rm DQ}$ = 125 mA, $P_{\rm OUT}$ = 60 W Pulsed
Dynamic Characteristics						
Input Capacitance <sup>7</sup>	C <sub>GS</sub>	-	15.3	-	pF	$V_{DS}$ = 50 V, $V_{gs}$ = -8 V, f = 1 MHz
Output Capacitance <sup>7</sup>	C <sub>DS</sub>	-	4.7	-	pF	$V_{DS} = 50 \text{ V, } V_{gs} = -8 \text{ V, f} = 1 \text{ MHz}$
Feedback Capacitance	$C_{GD}$	-	0.5	-	pF	$V_{DS}$ = 50 V, $V_{gs}$ = -8 V, f = 1 MHz

#### Notes:

<sup>&</sup>lt;sup>1</sup> Current limit for long term, reliable operation.

<sup>&</sup>lt;sup>2</sup> Refer to the Application Note on soldering at <a href="http://www.cree.com/rf/document-library">http://www.cree.com/rf/document-library</a>

<sup>&</sup>lt;sup>3</sup> Measured for the CGHV27060MP

 $<sup>^{\</sup>rm 4}$  See also, the Power Dissipation De-rating Curve on Page 4.

<sup>&</sup>lt;sup>1</sup> Measured on wafer prior to packaging.

<sup>&</sup>lt;sup>2</sup> Scaled from PCM data.

 $<sup>^3</sup>$  Pulse Width = 100  $\mu$ s, Duty Cycle = 10%

 $<sup>^4</sup>P_{SAT}$  is defined as  $I_{GS} = 1.0$  mA peak

<sup>&</sup>lt;sup>5</sup> Measured in CGHV27060MP-TB.

 $<sup>^6</sup>$  Single Carrier WCDMA, 3GPP Test Model 1, 64 DPCH, 45% Clipping, PAR = 7.5 dB @ 0.01% Probability on CCDF,  $V_{DD}$  = 50 V.

<sup>&</sup>lt;sup>7</sup> Includes package.



### **Typical Performance**

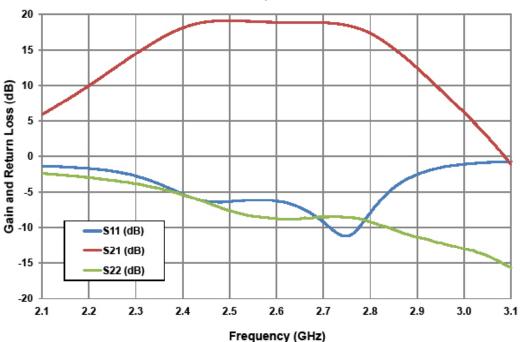
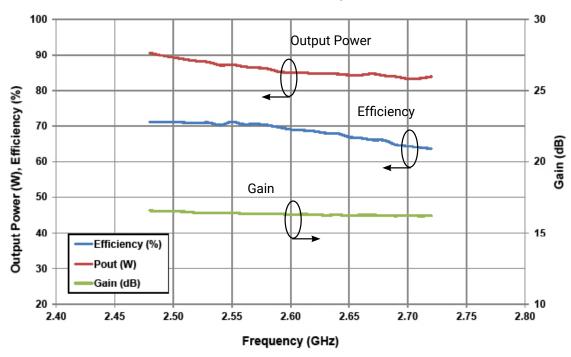


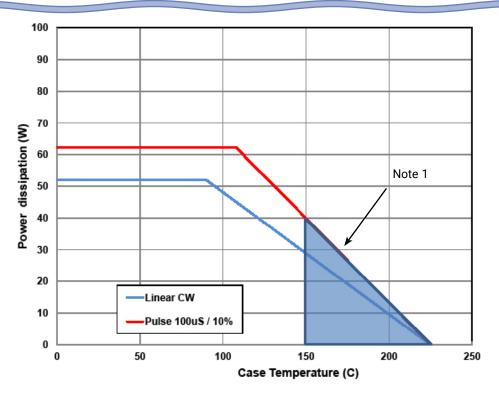
Figure 1. - Small Signal Gain and Return Losses of the CGHV27060MP Measured in Demonstration Amplifier Circuit CGHV27060MP-TB

Figure 2. - Gain, Power Added Efficiency & Average Power Output at 10% Duty Cycle for the CGHV27060MP Measured in Demonstration Amplifier Circuit CGHV27060MP-TB





# **CGHV27060MP Power Dissipation De-rating Curve**



Note 1. Area exceeds Maximum Case Temperature (See Page 2).

### **Electrostatic Discharge (ESD) Classifications**

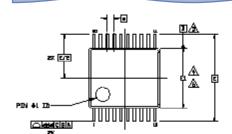
Parameter	Symbol	Class	Test Methodology
Human Body Model	НВМ	1A (> 250 V)	JEDEC JESD22 A114-D
Charge Device Model	CDM	2 (125 V to 250 V)	JEDEC JESD22 C101-C

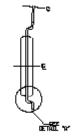
# Moisture Sensitivity Level (MSL) Classification

Parameter	Symbol	Level	Test Methodology
Moisture Sensitivity Level	MSL	3 (168 hours)	IPC/JEDEC J-STD-20



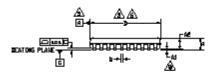
### Product Dimensions CGHV27060MP (4.4 mm TSSOP 20-Lead Package)

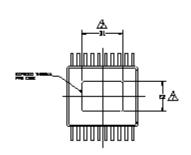


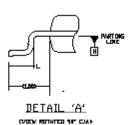


### NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS (ANGLES IN DEGREES).
- 2. DIMENSIONING & TOLERANCES PER ASME, YL4.5M-1994.
- $\Delta$  dimension of does not include mold flash, frotrusions or gate burrs. Mold flash, protrucions or gate burrs shall not exceed 0.15 per side.
- AD DIMENSION EL' DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 PER SIDE
- 🙆 DATUMO A AND 8 TO BE DETERMINED AT DATUM FLANE H.
- 🙆 DIMENSIONS for AND fey to be determined at datum plane H.
- $\Delta$ /D1, AND Æ2, DIMENSIONS DO NOT INCLUDE HOLD FLASH.
- $\stackrel{lack}{\triangle}$  at is defined as the vertical clearance from the seating plane to the lowest point on the package body.







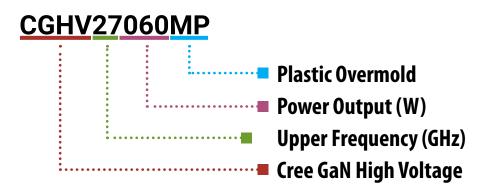
Ţ	COMMON			
1 '. 1		DIMENSIONS		
	MTN.	N⊓M.	MAX.	\ <u>'</u> =
Α			1.10	
A	0.05		0.15	8
A	0.85	0.90	0.95	
and		0.076		
Ь	0.19	-	0.30	
_	0.09	1	0.20	
	6.40	6.50	6.60	3,6
E1	4.30	4.40	4.50	4,6
e		<b>728 CAO</b>		
Е		6.40 BSC		
L	۵5۱	0.60	8.70	
11	4.10	4.20	4.30	7
EZ	290	3.00	3.10	7
ddd		0.20		

PIN	FUNCTION
1	GNII
2	GNI
3	I RF INPUT
4	RF INPUT
5	RE INPUT
- 6	RE INPLIT
	L RE INPUT
	RF_INPUT
- 7	GNI
10	GNI
<u> 11</u>	GNI
12	I SE SNUT
- +4	RE DUTPUT
<del>- 14</del> -	RE DUTPUT
16	RE DUTPUT
10	RF UUTPUT
16	<del>  \$\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ </del>
19	EN DOLLO
20	GNII
	LINI

PINDUT TABLE



## **Part Number System**



Parameter	Value	Units
Upper Frequency <sup>1</sup>	2.7	GHz
Power Output	60	W
Package	MP	-

Table 1.

**Note**<sup>1</sup>: Alpha characters used in frequency code indicate a value greater than 9.9 GHz. See Table 2 for value.

Character Code	Code Value
А	0
В	1
С	2
D	3
Е	4
F	5
G	6
Н	7
J	8
K	9
Examples:	1A = 10.0 GHz 2H = 27.0 GHz

Table 2.



# **Product Ordering Information**

Order Number	Description	Unit of Measure	lmage
CGHV27060MP	GaN HEMT	Each	CONTRACTOR OF THE PARTY OF THE
CGHV27060MP-AMP1	Test board with GaN HEMT installed	Each	



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